

Statistical Learning Theory Notes

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1 Probability settings

1.1 Classification problem

Definition 1.1 (Classifier (h)).

In **classification problems**, we consider pairs (x, y) where $x \in \mathcal{X}$ and $y \in \mathcal{Y}$. Where:

- \mathcal{X} is the space of **feature vectors**.
- \mathcal{Y} is the space of **labels**.

A classifier is a function $h : \mathcal{X} \rightarrow \mathcal{Y}$ which aims to assign correct labels to given feature vectors.

Remark : The key assumptions of classification problems are:

- There exists a joint distribution P_{XY} on $\mathcal{X} \times \mathcal{Y}$.
- The pairs (x, y) (observed data) are random samples of the random variables pair (X, Y) which has the distribution P_{XY} .

Definition 1.2 (Decomposition of P_{XY}).

We can decompose P_{XY} in either of the following two ways:

$$\begin{aligned} P_{XY} &= P_{X|Y} P_Y \\ P_{XY} &= P_{Y|X} P_X \end{aligned}$$

Which can be understood as two possible ways to generate the pairs (x, y) from the joint distribution P_{XY} .

- The first way is to generate a random label $y \sim P_Y$. Then, generate the feature vector corresponding to that label $x \sim P_{X|Y=y}$.
- The second way is to generate a random vector $x \sim P_X$. Then, generate the label corresponding to that feature vector $y \sim P_{Y|X=x}$.

Proposition 1.1: Law of total expectation

Given $\phi : \mathcal{X} \times \mathcal{Y} \rightarrow \mathbb{R}$. The **law of total expectation** states that:

$$\begin{aligned} \mathbb{E}_{XY} [\phi(X, Y)] &= \mathbb{E}_Y [\mathbb{E}_{X|Y} [\phi(X, Y)]] \\ &= \mathbb{E}_X [\mathbb{E}_{Y|X} [\phi(X, Y)]] \end{aligned}$$

Similar to how P_{XY} is decomposed, law of total expectation describes two way of taking the average value:

- Loop through the labels and take average over the feature vectors corresponding to each label.
- Loop through the feature vectors and take average over the labels corresponding to each vector.

Proof (Proposition 1.1).

We have:

$$\begin{aligned}
\mathbb{E}_{XY}[\phi(X, Y)] &= \int_{\mathcal{X}} \int_{\mathcal{Y}} \phi(x, y) P_{XY}(x, y) dy dx \\
&= \int_{\mathcal{X}} \int_{\mathcal{Y}} \phi(x, y) P_X(x) P_{Y|X}(y|x) dy dx \\
&= \int_{\mathcal{X}} P_X(x) \int_{\mathcal{Y}} \phi(x, y) P_{Y|X}(y|x) dy dx \\
&= \int_{\mathcal{X}} P_X(x) \mathbb{E}_{Y|X=x}[\phi(X, Y)] dx \\
&= \mathbb{E}_X[\mathbb{E}_{Y|X}[\phi(X, Y)]]
\end{aligned}$$

Applying the same technique, we have $\mathbb{E}_{XY}[\phi(X, Y)] = \mathbb{E}_Y[\mathbb{E}_{X|Y}[\phi(X, Y)]]$. \square .

Remark : Usually, the label space is discrete and finite, meaning $\mathcal{Y} = \{0, 1, 2, \dots, m\}$ for some $m < \infty$. Hence, the expectations over Y can be written as discrete sums:

$$\begin{aligned}
\mathbb{E}_{XY}[\phi(X, Y)] &= \mathbb{E}_Y[\mathbb{E}_{X|Y}[\phi(X, Y)]] = \sum_{y \in \mathcal{Y}} \mathbb{E}_{X|Y=y}[\phi(X, Y)] \\
&= \mathbb{E}_X[\mathbb{E}_{Y|X}[\phi(X, Y)]] = \mathbb{E}_X\left[\sum_{y \in \mathcal{Y}} \mathbb{E}_{Y=y|X}[\phi(X, Y)]\right]
\end{aligned}$$

Definition 1.3 (Hypothesis space (\mathcal{H})).

The hypothesis space is a collection (family) of classifiers $h : \mathcal{X} \rightarrow \mathcal{Y}$ that have some common properties:

$$\mathcal{H} = \left\{ h : \mathcal{X} \rightarrow \mathcal{Y} \mid \text{some common properties} \right\}$$

For example, let $\mathcal{X} = \mathbb{R}^d, \mathcal{Y} = (0, 1)$. In logistic regression, we assume the classifiers to be logit functions:

$$\mathcal{H}_{\text{logit}} = \left\{ h : \mathbb{R}^d \rightarrow (0, 1) \mid h(x) = \text{logit}(\beta x) = \frac{1}{1 + e^{-\beta x}}, \beta \in \mathbb{R}^{1 \times d} \right\}$$

Definition 1.4 (Learning algorithm (\mathcal{L}_n)).

To learn a classifier $h : \mathcal{X} \rightarrow \mathcal{Y}$, suppose that we have access to a training dataset of n data pairs $\{(X_k, Y_k)\}_{k=1}^n$ which are assumed to be **i.i.d sampled from** P_{XY} . The domain of the training data is then $(\mathcal{X} \times \mathcal{Y})^n$. A **learning algorithm**, denoted as \mathcal{L}_n is a function/procedure that derives a classifier $\hat{h}_n : \mathcal{X} \rightarrow \mathcal{Y}$ from the training data.

$$\begin{aligned}
\mathcal{L}_n &: (\mathcal{X} \times \mathcal{Y})^n \rightarrow \mathcal{H} \\
\hat{h}_n &= \mathcal{L}_n((X_1, Y_1), \dots, (X_n, Y_n))
\end{aligned}$$

1.2 Goal of classification

Definition 1.5 (Risk ($R(h)$)).

The **risk** of a classifier is defined as followed:

$$R(h) = P(h(X) \neq Y) = \mathbb{E}[\mathbf{1}_{\{h(X) \neq Y\}}]$$

Where (X, Y) are independent of the training data.

Definition 1.6 (Bayes Risk (R^*)).

The **Bayes risk** is the infimum of the risk taken over all $h : \mathcal{X} \rightarrow \mathcal{Y}$, not just for $h \in \mathcal{H}$:

$$R^* = \inf_{h: \mathcal{X} \rightarrow \mathcal{Y}} R(h)$$

Definition 1.7 (Consistency of learning algorithms).

A learning algorithm \mathcal{L}_n is called:

- **Weakly consistent** if $R(\hat{h}_n) \xrightarrow{P} R^*$:

$$\lim_{n \rightarrow \infty} P(R(\hat{h}_n) \leq r) = P(R^* \leq r), \quad \forall r \geq 0$$

- **Strongly consistent** if $R(\hat{h}_n) \xrightarrow{a.s.} R^*$:

$$P\left(\lim_{n \rightarrow \infty} |R(\hat{h}_n) - R^*| \geq \epsilon\right) = 0, \quad \forall \epsilon > 0$$

- **Universally weakly/strongly consistent** if \mathcal{L}_n is weakly/strongly consistent for all P_{XY} .
Meaning, consistency holds without any assumption about P_{XY} .

2 Bayes classifier

2.1 Properties of Bayes Risk

Overview : Recall that the Bayes classifier is the one with minimum risk and the corresponding risk is called the Bayes Risk. For $\mathcal{Y} = \{0, 1\}$ and defined:

$$\eta(x) = P(Y = 1|X = x)$$

Define the following classifier:

$$h^*(x) = \begin{cases} 1 & \text{if } \eta(x) \geq \frac{1}{2} \\ 0 & \text{otherwise} \end{cases}$$

Theorem 2.1: Properties of Bayes classifier

The following properties hold for the Bayes classifier with $\mathcal{Y} = \{0, 1\}$ (Binary classification):

- (i) $R(h^*) = \inf_{h: \mathcal{X} \rightarrow \mathcal{Y}} \{R(h)\} = R^*$.
- (ii) $\underbrace{R(h) - R^*}_{\text{Excess risk}} = 2\mathbb{E}_X \left[\left| \eta(x) - \frac{1}{2} \right| \mathbf{1}_{\{h(X) \neq h^*(X)\}} \right]$.
- (iii) $R^* = \mathbb{E} [\min(\eta(X), 1 - \eta(X))]$.

Proof (Theorem 2.1). _____

Proving each point:

$$(i) \ R(h^*) = \inf_{h: \mathcal{X} \rightarrow \mathcal{Y}} \{R(h)\} = R^*.$$

For all $h: \mathcal{X} \rightarrow \mathcal{Y}$, we have:

$$\begin{aligned} R(h) &= \mathbb{E}_{XY} [\mathbf{1}_{\{h(X) \neq Y\}}] \\ &= \mathbb{E}_{x \sim X} \left[\mathbb{E}_{Y|X=x} [\mathbf{1}_{\{Y \neq h(x)\}}] \right] \\ &= \mathbb{E}_{x \sim X} \left[\sum_{y \in \{0,1\}} \mathbf{1}_{\{y \neq h(x)\}} \right] \\ &= \mathbb{E}_{x \sim X} [\eta(x) \mathbf{1}_{\{h(x)=0\}} + (1 - \eta(x)) \mathbf{1}_{\{h(x)=1\}}] \end{aligned}$$

Since the two events $\{h(x) = 1\}$ and $\{h(x) = 0\}$ are mutually exclusive, $R(h)$ is the smallest when we set $h(x) = 1$ when $\eta(x) \geq 1 - \eta(x) \implies \eta(x) \geq \frac{1}{2}$. Therefore, we have:

$$h^*(x) = \begin{cases} 1 & \text{if } \eta(x) \geq \frac{1}{2} \\ 0 & \text{otherwise} \end{cases}$$

$$(ii) \ \underbrace{R(h) - R^*}_{\text{Excess risk}} = 2\mathbb{E}_X \left[\left| \eta(x) - \frac{1}{2} \right| \mathbf{1}_{\{h(X) \neq h^*(X)\}} \right].$$

We have:

$$\begin{aligned}
R(h) - R^* &= \mathbb{E}_{x \sim X} \left[\mathbb{E}_{Y|X=x} \left[\mathbf{1}_{\{Y \neq h(x)\}} \right] \right] - \mathbb{E}_{x \sim X} \left[\mathbb{E}_{Y|X=x} \left[\mathbf{1}_{\{Y \neq h^*(x)\}} \right] \right] \\
&= \mathbb{E}_{x \sim X} \left[\sum_{y \in \{0,1\}} \mathbf{1}_{\{y \neq h(x)\}} P(Y = y|X = x) \right] - \mathbb{E}_{x \sim X} \left[\sum_{y \in \{0,1\}} \mathbf{1}_{\{y \neq h^*(x)\}} P(Y = y|X = x) \right] \\
&= \mathbb{E}_{x \sim X} \left[\eta(x) \left(\mathbf{1}_{\{h(x)=0\}} - \mathbf{1}_{\{h^*(x)=0\}} \right) + (1 - \eta(x)) \left(\mathbf{1}_{\{h(x)=1\}} - \mathbf{1}_{\{h^*(x)=1\}} \right) \right] \\
&= \mathbb{E}_{x \sim X} \left[\eta(x) \left(\mathbf{1}_{\{h(x) \neq h^*(x), h(x)=0\}} - \mathbf{1}_{\{h(x) \neq h^*(x), h(x)=1\}} \right) \right. \\
&\quad \left. + (1 - \eta(x)) \left(\mathbf{1}_{\{h(x) \neq h^*(x), h(x)=1\}} - \mathbf{1}_{\{h(x) \neq h^*(x), h(x)=0\}} \right) \right] \\
&= \mathbb{E}_{x \sim X} \left[(2\eta(x) - 1) \mathbf{1}_{\{h(x) \neq h^*(x), h(x)=0\}} + (1 - 2\eta(x)) \mathbf{1}_{\{h(x) \neq h^*(x), h(x)=1\}} \right] \\
&= \mathbb{E}_{x \sim X} \left[\left| 2\eta(x) - 1 \right| \mathbf{1}_{\{h(x) \neq h^*(x)\}} \right] \\
&= 2\mathbb{E}_X \left[\left| \eta(X) - \frac{1}{2} \right| \mathbf{1}_{\{h(X) \neq h^*(X)\}} \right]
\end{aligned}$$

$$(iii) \quad R^* = \mathbb{E} \left[\min(\eta(X), 1 - \eta(X)) \right].$$

From (i) we have:

$$\begin{aligned}
R(h^*) &= \mathbb{E}_{x \sim X} \left[\eta(x) \mathbf{1}_{\{h^*(x)=0\}} + (1 - \eta(x)) \mathbf{1}_{\{h^*(x)=1\}} \right] \\
&= \mathbb{E}_X \left[\min(\eta(X), 1 - \eta(X)) \right]
\end{aligned}$$

□.

Theorem 2.2: Properties of Bayes classifier (Multi-class)

For multi-class classification with more than two labels : $\mathcal{Y} = \{1, 2, \dots, M\}$, the Bayes classifier is defined as followed:

$$h^*(x) = \arg \max_{y \in \mathcal{Y}} \left\{ \eta_y(x) \right\}$$

$$\text{Where : } \eta_y(x) = P(Y = y | X = x)$$

The following properties hold for the Bayes classifier with $\mathcal{Y} = \{1, 2, \dots, M\}$ (Multi-class classification):

- (i) **Bayes Risk** R^* :

$$R^* = \mathbb{E}_{x \sim X} \left[1 - \max_{y \in \mathcal{Y}} \left\{ \eta_y(x) \right\} \right] = \mathbb{E}_{x \sim X} \left[\min_{y \in \mathcal{Y}} \overline{\eta}_y(x) \right]$$

- (ii) **Excess Risk** $R(h) - R^*$:

$$R(h) - R^* = \mathbb{E}_X \left[\left(\eta_{y_x^*}(x) - \eta_{y_x}(x) \right) \mathbf{1}_{\{h(x) \neq h^*(x)\}} \right]$$

Where $y_x = h(x)$ is the prediction made by an arbitrary classifier $h : \mathcal{X} \rightarrow \mathcal{Y}$ and $y_x^* = h^*(x)$ is the prediction made by the Bayes classifier.

Proof (Theorem 2.2).

(The proof of this theorem has been included in the solution of Exercise 2.1).

□.

2.2 Likelihood Ratio Test

Overview : Define $\pi_1 = P(Y = 1)$ and $\pi_0 = P(Y = 0)$ be the prior probabilities. Let $p_1(x) = P(X = x | Y = 1)$ and $p_0(x) = P(X = x | Y = 0)$ be the class-conditional densities. Note that we have:

$$\begin{aligned} \eta(x) &= P(Y = 1 | X = x) \\ &= \frac{P(X = x | Y = 1)P(Y = 1)}{P(X = x | Y = 1)P(Y = 1) + P(X = x | Y = 0)P(Y = 0)} \\ &= \frac{\pi_1 p_1(x)}{\pi_1 p_1(x) + \pi_0 p_0(x)} \\ &= \frac{1}{1 + \frac{\pi_0 p_0(x)}{\pi_1 p_1(x)}} \end{aligned}$$

Hence, we have:

$$\begin{aligned} \eta(x) \geq \frac{1}{2} &\iff \frac{\pi_0 p_0(x)}{\pi_1 p_1(x)} \\ &\iff \frac{p_1(x)}{p_0(x)} \geq \frac{\pi_0}{\pi_1} \end{aligned}$$

Proposition 2.1: Likelihood ratio test

The Bayes classifier h^* can be re-defined as followed:

$$h^*(x) = \begin{cases} 1 & \text{if } \frac{p_1(x)}{p_0(x)} \geq \frac{\pi_0}{\pi_1} \\ 0 & \text{otherwise} \end{cases}$$

The fraction $\frac{p_1(x)}{p_0(x)}$ is called the **likelihood ratio**.

2.3 Plug-in classifier

Definition 2.1 (Plug-in classifier).

A **plug-in classifier** is based on an estimate of $\eta(x)$. This estimate is then plugged into the definition of the Bayes classifier. Suppose that $\widehat{\eta}_n$ is an estimate of η based on n training samples $\{(X_i, Y_i)\}_{i=1}^n$. We define \widehat{h}_n as:

$$\widehat{h}_n = \begin{cases} 1 & \text{if } \widehat{\eta}_n(x) \geq \frac{1}{2} \\ 0 & \text{otherwise} \end{cases}$$

Corollary 2.1: Excess risk of plug-in classifier

We have the following upper-bound for the excess risk of the plug-in classifier:

$$R(\widehat{h}_n) - R^* \leq 2\mathbb{E}_X \left[\left| \eta(X) - \widehat{\eta}_n(X) \right| \right]$$

Proof (Corollary 2.1).

From theorem 2.1, we have:

$$R(\widehat{h}_n) - R^* = 2\mathbb{E}_X \left[\left| \eta(X) - \frac{1}{2} \right| \mathbf{1}_{\{\widehat{h}_n(X) \neq h^*(X)\}} \right]$$

The indicator term will be non-zero in the above equality if one of the following cases occurs:

$$\begin{cases} \widehat{h}_n(X) = 1, h^*(X) = 0 \\ \widehat{h}_n(X) = 0, h^*(X) = 1 \end{cases} \implies \begin{cases} \widehat{\eta}_n(X) \geq \frac{1}{2}, \eta(X) < \frac{1}{2} \\ \widehat{\eta}_n(X) < \frac{1}{2}, \eta(X) \geq \frac{1}{2} \end{cases}$$

Case 1 : $\widehat{\eta}_n(X) \geq \frac{1}{2}, \eta(X) < \frac{1}{2}$

We have:

$$\begin{aligned} \eta(X) - \widehat{\eta}_n(X) &\leq \eta(X) - \frac{1}{2} \quad (\text{Both sides negative}) \\ \implies \left| \eta(X) - \widehat{\eta}_n(X) \right| &\geq \left| \eta(X) - \frac{1}{2} \right| \end{aligned}$$

Case 2 : $\widehat{\eta}_n(X) < \frac{1}{2}, \eta(X) \geq \frac{1}{2}$

We have:

$$\widehat{\eta}_n(X) - \eta(X) \geq \widehat{\eta}_n(X) - \frac{1}{2} \geq \eta(X) - \frac{1}{2} \quad (\text{All positive})$$

Therefore, we have:

$$\left| \eta(X) - \widehat{\eta}_n(X) \right| \geq \left| \eta(X) - \frac{1}{2} \right|$$

For both cases, we have the same $\left| \eta(X) - \widehat{\eta}_n(X) \right| \geq \left| \eta(X) - \frac{1}{2} \right|$ inequality. Therefore, we have:

$$R(\widehat{h}_n) - R^* \leq 2\mathbb{E}_X \left[\left| \eta(X) - \widehat{\eta}_n(X) \right| \right]$$

□.

2.4 End of chapter exercises

Exercise 2.1

Extend theorem 2.1 to the multi-class classification case where $\mathcal{Y} = \{1, 2, \dots, M\}$. In other words, prove theorem 2.2.

Solution (Exercise 2.1).

We re-define the Bayes classifier h^* as followed:

$$h^*(x) = \arg \max_{y \in \mathcal{Y}} \{\eta_y(x)\},$$

$$\eta_y(x) = P(Y = y | X = x)$$

We have:

$$\sum_{y \in \mathcal{Y}} \eta_y(x) = 1, \quad \forall x \in \mathcal{X}$$

(i) **Calculate Bayes risk R^***

For any classifier $h : \mathcal{X} \rightarrow \mathcal{Y}$, we have:

$$R(h) = \mathbb{E}_{x \sim X} \left[\sum_{y \in \mathcal{Y}} \mathbf{1}_{\{h(x) \neq y\}} \eta_y(x) \right]$$

Letting $\hat{y}_x = h(x)$ being h 's prediction for a given feature vector $x \in \mathcal{X}$, we have:

$$R(h) = \mathbb{E}_{x \sim X} \left[\sum_{y \in \mathcal{Y}; y \neq \hat{y}_x} \eta_y(x) \right] = \mathbb{E}_{x \sim X} \left[1 - \eta_{\hat{y}_x}(x) \right]$$

In order to minimize $R(h)$, we need $\eta_{\hat{y}_x}(x)$ to be maximized for all $x \in \mathcal{X}$. Hence, we have:

$$R^* = \mathbb{E}_{x \sim X} \left[1 - \max_{y \in \mathcal{Y}} \{\eta_y(x)\} \right]$$

Therefore, we have $h^*(x) = \arg \max_{y \in \mathcal{Y}} \{\eta_y(x)\}$ is the Bayes classifier and the Bayes risk $R^* = \mathbb{E}_{x \sim X} \left[1 - \max_{y \in \mathcal{Y}} \{\eta_y(x)\} \right]$.

(ii) **Calculate excess risk $R(h) - R^*$**

For any $h : \mathcal{X} \rightarrow \mathcal{Y}$, we have:

$$\begin{aligned} R(h) - R^* &= \mathbb{E}_{x \sim X} \left[\sum_{y \in \mathcal{Y}} \mathbf{1}_{\{h(x) \neq y\}} \eta_y(x) \right] - \mathbb{E}_{x \sim X} \left[1 - \max_{y \in \mathcal{Y}} \{\eta_y(x)\} \right] \\ &= \mathbb{E}_{x \sim X} \left[\sum_{y \in \mathcal{Y}} \mathbf{1}_{\{h(x) \neq y\}} \eta_y(x) + \max_{y \in \mathcal{Y}} \{\eta_y(x)\} - 1 \right] \end{aligned}$$

Denote $h^*(x) = y_x^*$ and $h(x) = y_x$. When $h(x) = h^*(x) = y_x^*$, we have:

$$\begin{aligned}
\sum_{y \in \mathcal{Y}} \mathbf{1}_{\{h(x) \neq y\}} \eta_y(x) + \max_{y \in \mathcal{Y}} \{\eta_y(x)\} &= \sum_{y \in \mathcal{Y}; y \neq y_x} \eta_y(x) + \eta_{y_x^*}(x) \\
&= \sum_{y \in \mathcal{Y}; y \neq y_x^*} \eta_y(x) + \eta_{y_x^*}(x) \\
&= \sum_{y \in \mathcal{Y}} \eta_y(x) = 1 \\
\Rightarrow \sum_{y \in \mathcal{Y}} \mathbf{1}_{\{h(x) \neq y\}} \eta_y(x) + \max_{y \in \mathcal{Y}} \{\eta_y(x)\} - 1 &= 0
\end{aligned}$$

When $h(x) \neq h^*(x)$, we have:

$$\begin{aligned}
\sum_{y \in \mathcal{Y}} \mathbf{1}_{\{h(x) \neq y\}} \eta_y(x) + \max_{y \in \mathcal{Y}} \{\eta_y(x)\} - 1 &= \sum_{y \in \mathcal{Y}; y \neq y_x} \eta_y(x) + \eta_{y_x^*}(x) - 1 \\
&= 2\eta_{y_x^*}(x) - 1 + \sum_{y \in \mathcal{Y} \setminus \{y_x, y_x^*\}} \eta_y(x) \\
&= 2\eta_{y_x^*}(x) - (\eta_{y_x}(x) + \eta_{y_x^*}(x)) \\
&= \eta_{y_x^*}(x) - \eta_{y_x}(x).
\end{aligned}$$

Therefore, we can re-write the excess risk by multiplying the entire integrand with the indicator function $\mathbf{1}_{\{h(x) \neq h^*(x)\}}$ as followed:

$$R(h) - R^* = \mathbb{E}_{x \sim X} \left[\left(\eta_{y_x^*}(x) - \eta_{y_x}(x) \right) \mathbf{1}_{\{h(x) \neq h^*(x)\}} \right]$$

(iii) Simpler form of Bayes risk

From (i) we have:

$$R^* = \mathbb{E}_X \left[1 - \max_{y \in \mathcal{Y}} \{\eta_y(x)\} \right] = \mathbb{E}_X \left[\min_{y \in \mathcal{Y}} \{\bar{\eta}_y(x)\} \right]$$

Where $\bar{\eta}_y(x) = P(Y \neq y | X = x)$.

□.

Exercise 2.2

Define the α -cost-sensitive risk of a classifier $h : \mathcal{X} \rightarrow \mathcal{Y}$ as followed:

$$R_\alpha(h) = \mathbb{E}_{XY} \left[(1 - \alpha) \mathbf{1}_{\{Y=1, h(X)=0\}} + \alpha \mathbf{1}_{\{Y=0, h(X)=1\}} \right]$$

Define the Bayes classifier and prove an analogue of theorem 2.1.

Solution (Exercise 2.2).

Using the law of total expectation, we have:

$$\begin{aligned}
R_\alpha(h) &= \mathbb{E}_{x \sim X} \left[\sum_{y \in \{0,1\}} \left[(1 - \alpha) \mathbf{1}_{\{y=1, h(x)=0\}} + \alpha \mathbf{1}_{\{y=0, h(x)=1\}} \right] P(Y = y | X = x) \right] \\
&= \mathbb{E}_{x \sim X} \left[(1 - \alpha) \eta(x) \mathbf{1}_{\{h(x)=0\}} + \alpha (1 - \eta(x)) \mathbf{1}_{\{h(x)=1\}} \right]
\end{aligned}$$

Since $\mathbf{1}_{\{h(x)=0\}}$ and $\mathbf{1}_{\{h(x)=1\}}$ are mutually exclusive, in order for $R_\alpha(h)$ to be minimize, we define the following Bayes classifier:

$$h^*(x) = \begin{cases} 1 & \text{if } \alpha(1 - \eta(x)) \leq (1 - \alpha)\eta(x) \\ 0 & \text{otherwise} \end{cases} = \begin{cases} 1 & \text{if } \eta(x) \geq \alpha \\ 0 & \text{otherwise} \end{cases}$$

We can also derive a likelihood-ratio test version of the Bayes classifier, we have:

$$\begin{aligned} \eta(x) \geq \alpha &\implies \frac{1}{1 + \frac{\pi_0 p_0(x)}{\pi_1 p_1(x)}} \geq \alpha \\ &\implies 1 + \frac{\pi_0 \cdot p_0(x)}{\pi_1 \cdot p_1(x)} \leq \frac{1}{\alpha} \\ &\implies \frac{p_1(x)}{p_0(x)} \geq \frac{\alpha}{1 - \alpha} \cdot \frac{\pi_0}{\pi_1} \end{aligned}$$

Hence, we can rewrite the Bayes classifier as followed:

$$h^*(x) = \begin{cases} 1 & \text{if } \frac{p_1(x)}{p_0(x)} \geq \frac{\alpha}{1 - \alpha} \cdot \frac{\pi_0}{\pi_1} \\ 0 & \text{otherwise} \end{cases}$$

(i) **Bayes Risk** R_α^*

We have:

$$\begin{aligned} R_\alpha^* &= R_\alpha(h^*) \\ &= \mathbb{E}_{x \sim X} \left[(1 - \alpha)\eta(x)\mathbf{1}_{\{h^*(x)=0\}} + \alpha(1 - \eta(x))\mathbf{1}_{\{h^*(x)=1\}} \right] \\ &= \mathbb{E}_X \left[\min(\alpha(1 - \eta(X)), (1 - \alpha)\eta(X)) \right] \end{aligned}$$

(ii) **Excess Risk** $R_\alpha(h) - R_\alpha^*$

For an arbitrary $h : \mathcal{X} \rightarrow \mathcal{Y}$, we have:

$$\begin{aligned} R_\alpha(h) - R_\alpha^* &= \mathbb{E}_{x \sim X} \left[(1 - \alpha)\eta(x) \left(\mathbf{1}_{\{h(x)=0\}} - \mathbf{1}_{\{h^*(x)=0\}} \right) + \alpha(1 - \eta(x)) \left(\mathbf{1}_{\{h(x)=1\}} - \mathbf{1}_{\{h^*(x)=1\}} \right) \right] \\ &= \mathbb{E}_{x \sim X} \left[(1 - \alpha)\eta(x) \left(\mathbf{1}_{\{h(x)=0, h^*(x)=1\}} - \mathbf{1}_{\{h(x)=1, h^*(x)=0\}} \right) \right. \\ &\quad \left. + \alpha(1 - \eta(x)) \left(\mathbf{1}_{\{h(x)=1, h^*(x)=0\}} - \mathbf{1}_{\{h(x)=0, h^*(x)=1\}} \right) \right] \\ &= \mathbb{E}_{x \sim X} \left[\mathbf{1}_{\{h(x)=0, h^*(x)=1\}} (\eta(x) - \alpha) + \mathbf{1}_{\{h(x)=1, h^*(x)=0\}} (\alpha - \eta(x)) \right] \\ &= \mathbb{E}_X \left[\left| \eta(X) - \alpha \right| \mathbf{1}_{\{h(X) \neq h^*(X)\}} \right] \end{aligned}$$

□.

3 Hoeffding's inequality

3.1 Markov's Inequality

Proposition 3.1: Markov's Inequality

Let U be a non-negative random variable on \mathbb{R} , then for all $t > 0$, we have:

$$P(U \geq t) \leq \frac{1}{t} \mathbb{E}[U]$$

Proof (Proposition 3.1). _____

We have:

$$\begin{aligned} tP(U \geq t) &= t\mathbb{E}[\mathbf{1}_{\{U \geq t\}}] \\ &= t \int_0^\infty \mathbf{1}_{\{x \geq t\}} f_U(x) dx \\ &= t \int_t^\infty f_U(x) dx \\ &\leq \int_t^\infty x f_U(x) dx \\ &\leq \int_0^\infty x f_U(x) dx = \mathbb{E}[U] \\ \implies P(U \geq t) &\leq \frac{1}{t} \mathbb{E}[U] \end{aligned}$$

□.

Corollary 3.1: Chebyshev's Inequality

Let Z be a random variable on \mathbb{R} with mean μ and variance σ^2 , we have:

$$P(|Z - \mu| \geq t) \leq \frac{\sigma^2}{t^2}$$

Proof (Corollary 3.1). _____

Using Markov's inequality, we have:

$$\begin{aligned} P(|Z - \mu| \geq t) &= P(|Z - \mu|^2 \geq t^2) \\ &\leq \frac{\mathbb{E}[|Z - \mu|^2]}{t^2} = \frac{\sigma^2}{t^2} \end{aligned}$$

□.

Corollary 3.2: Chernoff's bounding method

Let Z be a random variable on \mathbb{E} , for any $t > 0$, we have:

$$P(Z \geq t) \leq \inf_{s>0} e^{-st} M_Z(s)$$

Proof (Corollary 3.2). _____

We have:

$$\begin{aligned}
P(Z \geq t) &= P(sZ \geq st), \quad (t > 0) \\
&= P(e^{sZ} \geq e^{st}) \\
&\leq \frac{\mathbb{E}[e^{sZ}]}{e^{st}} = e^{-st} M_Z(s) \quad (\text{Markov's inequality})
\end{aligned}$$

Since the above inequality holds for all $s > 0$, we can just take the infimum to obtain the tightest bound. Hence, we have:

$$P(Z \geq t) \leq \inf_{s>0} e^{-st} M_Z(s)$$

□.

3.2 Hoeffding's Inequality

Before diving into Hoeffding's inequality, we need to go through the following lemma (whose proof will not be included) that will help us prove the Hoeffding's inequality:

Lemma 3.1: Hoeffding's lemma

Let V be a random variable on \mathbb{R} with $\mathbb{E}[V] = 0$ and suppose that $a \leq V \leq b$ with probability one. We have:

$$\mathbb{E}[e^{sV}] \leq \exp\left(\frac{s^2(b-a)^2}{8}\right)$$

Proof (Lemma 3.1). _____
(The proof for this lemma can be found here [3]).

□.

Theorem 3.1: Hoeffding's Inequality

Let Z_1, Z_2, \dots, Z_n be independent random variables on \mathbb{R} such that $a_i \leq Z_i \leq b_i$ with probability one for all $1 \leq i \leq n$. Let $S_n = \sum_{i=1}^n Z_i$. We have:

$$P\left(|S_n - \mathbb{E}[S_n]| \geq t\right) \leq 2 \exp\left(-\frac{2t^2}{\sum_{i=1}^n (b_i - a_i)^2}\right), \quad \forall t > 0$$

Proof (Theorem 3.1). _____

Using the Chernoff's bounds, we have:

$$\begin{aligned}
P\left(\left|S_n - \mathbb{E}[S_n]\right| \geq t\right) &\leq \inf_{s>0} e^{-st} M_{S_n - \mathbb{E}[S_n]}(s) \\
&= \inf_{s>0} e^{-st} \mathbb{E}\left[e^{s(S_n - \mathbb{E}[S_n])}\right] \\
&= \inf_{s>0} e^{-st} \mathbb{E}\left[\exp\left(s \sum_{i=1}^n (Z_i - \mathbb{E}[Z_i])\right)\right] \\
&= \inf_{s>0} e^{-st} \mathbb{E}\left[\prod_{i=1}^n \exp\left(s(Z_i - \mathbb{E}[Z_i])\right)\right] \\
&= \inf_{s>0} e^{-st} \prod_{i=1}^n \mathbb{E}\left[\exp\left(s(Z_i - \mathbb{E}[Z_i])\right)\right] \quad (\text{Since all } Z_i - \mathbb{E}[Z_i] \text{ are independent}) \\
&\leq \inf_{s>0} e^{-st} \prod_{i=1}^n \exp\left(\frac{s^2(b_i - a_i)^2}{8}\right) \quad (\text{By Hoeffding's lemma}) \\
&= \inf_{s>0} \exp\left(-st + \sum_{i=1}^n \frac{s^2(b_i - a_i)^2}{8}\right)
\end{aligned}$$

In order for the above to be minimized, we differentiate the term inside the exponential and set the derivative to 0 to find the optimal $s > 0$. We have:

$$-t + s \sum_{i=1}^n \frac{(b_i - a_i)^2}{4} = 0 \implies s = \frac{4t}{\sum_{i=1}^n (b_i - a_i)^2}$$

Letting $c = \sum_{i=1}^n (b_i - a_i)^2$, we now can derive the tightest Chernoff's bound as followed:

$$\begin{aligned}
P\left(\left|S_n - \mathbb{E}[S_n]\right| \geq t\right) &\leq \exp\left(-\frac{4t^2}{c} + \frac{16t^2}{c^2} \cdot \frac{c}{8}\right) = \exp\left(-\frac{2t^2}{c}\right) \\
&= \exp\left(-\frac{2t^2}{\sum_{i=1}^n (b_i - a_i)^2}\right)
\end{aligned}$$

□.

3.3 Convergence of Empirical Risk

Definition 3.1 (Empirical Risk).

Suppose we are given training data $\{(X_i, Y_i)_{i=1}^n\}$ such that each pair $(X_i, Y_i) \sim P_{XY}$ are independently identically distributed. Let $h : \mathcal{X} \rightarrow \mathcal{Y}$ be a classifier. We define the **empirical risk** to be:

$$\widehat{R}_n(h) = \frac{1}{n} \sum_{i=1}^n \mathbf{1}_{\{h(X_i) \neq Y_i\}}$$

Note that $\mathbb{E}[\widehat{R}_n(h)] = R(h)$ and $n\widehat{R}_n(h) \sim \text{Binomial}(n, R(h))$. In the following corollary of the Hoeffding's inequality, we will answer the question **how close the empirical risk is as an estimate of true risk or how fast the empirical risk converges to the true risk**.

Corollary 3.3: Convergence of Empirical Risk

Given training data $\{(X_i, Y_i)_{i=1}^n\}$ such that each pair $(X_i, Y_i) \sim P_{XY}$ are independently identically distributed. Let $h : \mathcal{X} \rightarrow \mathcal{Y}$ be a classifier, we have:

$$P\left(\left|\widehat{R}_n(h) - R(h)\right| \geq \epsilon\right) \leq 2e^{-2n\epsilon^2}, \quad \epsilon > 0$$

Proof (Corollary 3.3).

For all $1 \leq i \leq n$, we have $\mathbf{1}_{\{h(X_i) \neq Y_i\}} \in \{0, 1\}$. Hence, with probability one, $0 \leq \mathbf{1}_{\{h(X_i) \neq Y_i\}} \leq 1$ and $b_i = 1, a_i = 0$ for all $1 \leq i \leq n$.

Using the Hoeffding's inequality, we have:

$$\begin{aligned} P\left(\left|\widehat{R}_n(h) - R(h)\right| \geq \epsilon\right) &= P\left(\left|\widehat{R}_n(h) - \mathbb{E}[\widehat{R}_n(h)]\right| \geq \epsilon\right) \\ &= P\left(\left|n\widehat{R}_n(h) - \mathbb{E}[n\widehat{R}_n(h)]\right| \geq n\epsilon\right) \\ &\leq \exp\left(-\frac{2n^2\epsilon^2}{\sum_{i=1}^n (b_i - a_i)^2}\right) \quad (\text{Hoeffding's inequality}) \\ &= e^{-2n\epsilon^2} \end{aligned}$$

□.

3.4 KL-divergence & Hypothesis Testing

Set-up (Hypothesis Testing) : Suppose that we have $\mathcal{Y} = \{0, 1\}$ and P_{XY} is a distribution on $\mathcal{X} \times \mathcal{Y}$. Let's assume that:

- The prior probabilities π_y are equal.
- The supports of likelihoods p_0, p_1 are the same.
- $0 < \alpha \leq p_y(x) \leq \beta < \infty$ for all $x \in \mathcal{X}$ such that $p_y(x) > 0$ and for all $y \in \{0, 1\}$.

Now suppose $X_1, \dots, X_n \sim p_y$ are independently identically distributed where $y \in \{0, 1\}$ is unknown. Can we guess y and how good our guess would be?

Proposition 3.2: KL-divergence hypothesis testing

From the above settings, the optimal classifier is given by the likelihood ratio test:

$$\widehat{h}_n(x) = \begin{cases} 1 & \text{if } \frac{\prod_{i=1}^n p_1(x_i)}{\prod_{i=1}^n p_0(x_i)} \geq \frac{\pi_0}{\pi_1} \quad (= 1) \\ 0 & \text{otherwise} \end{cases}$$

Where $x = (x_1, \dots, x_n)$ is an observation of the random vector $X = (X_1, \dots, X_n)$. Define the class-specific risk $R_y(h)$ be the risk of misclassification when the true label is $Y = y$:

$$R_y(h) = P(h(X) \neq Y | Y = y)$$

Then, we have:

$$R_0(\widehat{h}_n) \leq e^{-2nD(p_0||p_1)^2/c}, \text{ where } c = 4(\log \beta - \log \alpha)^2$$

Where $D(p_0||p_1)$ is the *KL*-divergence of p_1 from p_0 . We can prove a similar exponentially decaying bound for $R_1(\widehat{h}_n)$.

Proof.

Proposition 3.2 We can rewrite the optimal classifier as:

$$\widehat{h}_n(X) = \begin{cases} 1 & \text{if } \widehat{S}_n(X_1, \dots, X_n) \geq 0 \\ 0 & \text{otherwise} \end{cases}$$

Where we have:

$$\begin{aligned} \widehat{S}_n(X_1, \dots, X_n) &= \log \frac{\prod_{i=1}^n p_1(X_i)}{\prod_{i=1}^n p_0(X_i)} \\ &= \sum_{i=1}^n \log \frac{p_1(X_i)}{p_0(X_i)} \\ &= \sum_{i=1}^n Z_i \quad \left(\text{Letting } Z_i = \log \frac{p_1(X_i)}{p_0(X_i)} \right) \end{aligned}$$

Since the likelihoods are bounded, we have:

$$a_i = \log \frac{\alpha}{\beta} \leq Z_i \leq \log \frac{\beta}{\alpha} = b_i, \quad 1 \leq i \leq n$$

Now, we have:

$$\begin{aligned} R_0(\widehat{h}_n) &= P(h(X) \neq Y | Y = 0) \\ &= P(\widehat{S}_n \geq 0 | Y = 0) \\ &= P(\widehat{S}_n - \mathbb{E}[S_n | Y = 0] \geq -\mathbb{E}[S_n | Y = 0] | Y = 0) \end{aligned}$$

To calculate the conditional expectation $\mathbb{E}[S_n | Y = 0]$, we have:

$$\begin{aligned} \mathbb{E}[S_n | Y = 0] &= n\mathbb{E}[Z_1 | Y = 0] \\ &= n \int \log \frac{p_1(x)}{p_0(x)} p_0(x) dx \\ &= -n \int \log \frac{p_0(x)}{p_1(x)} p_0(x) dx = -nD(p_0||p_1) \end{aligned}$$

Therefore, we have:

$$\begin{aligned} R_0(\widehat{h}_n) &= P(\widehat{S}_n - \mathbb{E}[S_n|Y=0] \geq nD(p_0||p_1)|Y=0) \\ &\leq \exp\left(-\frac{2n^2D(p_0||p_1)^2}{\sum_{i=1}^n(b_i - a_i)^2}\right) \quad (\text{Hoeffding's inequality}) \end{aligned}$$

For every $1 \leq i \leq n$, we have:

$$\begin{aligned} b_i - a_i &= \log \frac{\beta}{\alpha} - \log \frac{\alpha}{\beta} \\ &= \log \frac{\beta^2}{\alpha^2} = 2 \log \frac{\beta}{\alpha} = 2(\log \beta - \log \alpha) \\ \implies \sum_{i=1}^n (b_i - a_i)^2 &= 4n(\log \beta - \log \alpha)^2 \end{aligned}$$

Finally, we have:

$$R_0(\widehat{h}_n) \leq \exp\left(-\frac{2nD(p_0||p_1)^2}{4(\log \beta - \log \alpha)^2}\right)$$

Similarly, for $R_1(\widehat{h}_n)$, we have:

$$R_1(\widehat{h}_n) \leq \exp\left(-\frac{2nD(p_1||p_0)^2}{4(\log \beta - \log \alpha)^2}\right)$$

□.

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E References

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